

Notice of References Cited	Application/Control No. 10/617,386	Applicant(s)/Patent Under Reexamination NAKANO ET AL.	
	Examiner Tom V. Sheng	Art Unit 2677	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-5,576,731	11-1996	Whitby et al.	345/100
*	D	US-5,349,368	09-1994	Takeda et al.	345/684
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	K	US-			
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	M	US-			

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NON-PATENT DOCUMENTS

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